



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: MIDDLEBROOKS, et al

Application No.: 10/665,980

Filed: September 19, 2003

For: CONTROL OF OVERLAY

REGISTRATION

Atty. Docket No.: MODEP001

Examiner: Unknown

Group: Unassigned

Date: October 10, 2003

CERTIFICATE OF MAILING

1450 on October 10, 2003.

Signed:

Pat Tate

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §§1.56 AND 1.97(b) BEFORE MAILING OF A FIRST OFFICE ACTION

Mail Stop _____ Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

This Information Disclosure Statement is being filed within three (3) months of the filing date of the above-referenced application. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 50-0685 (Order No. MODEP001).

Respectfully submitted,

VAN PELT & YI LLP

Diana Y. Fu

Reg. No. 52,924

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Form 1449 (Modified)

Information Disclosure Statement By Applicant Atty Docket No. Application No.:

. MODEP001 : 10/665,980

Inventor

MIDDLEBROOKS, et al

Group

unassigned

(Use Several Sheets if Necessary)

Filing Date September 19, 2003

U.S. Patent Documents

Examiner						Sub-	Filing
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Foreign Patent or Published Foreign Patent Application

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Examiner		Document	Publication	Country or		Sub-		lation
Initial	No.	No.	Date	Patent Office	Class	class	Yes	No
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Other Documents

Examiner		The Day Division of Duklication
Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	Middlebrooks, Scott A., "Optimal Model-Predictive Control of Overlay
		Lithography Implemented in an ASIC Fab" Proceedings of SPIE,
		Microlithography 2003, 5044-2
	ļ	
	S	Muske, Kenneth Robert, "Linear Model Predictive Control of Chemical
		Processes" University of Texas at Austin, May 1995.
	T	
Examiner		Date Considered
		it is a line through eitation if not in conformance and

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.